

80mΩ, 650V, Super Junction N-Channel Power MOSFET

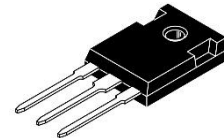
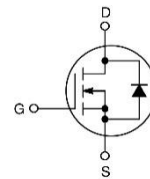
Description

The LXP SEMI LX1S080N065FBW is a high voltage power MOSFET, fabricated using advanced super junction technology. The resulting device has extremely low on resistance, low gate charge and fast switching time, making it especially suitable for applications which require superior power density and outstanding efficiency.

The LX1S080N065FBW break down voltage is 650V and it has a high rugged avalanche characteristic. The LX1S080N065FBW is available in TO-247-3 package.

Key Features

- Low $R_{DS(on)}$ =65mΩ @ $V_{GS} = 10V$.
- Ultra Low Gate Charge, $Q_g=60nC$ typ.
- Fast switching capability
- Robust design with better EAS performance
- Fast-Recovery Body Diode



TO-247-3

Applications

- Telecom Power
- EV Charger
- LED Lighting

Key performance

Parameter	Value	Unit
$V_{DS}(T_j=25^{\circ}C)$	650	V
$R_{DS(on), max}(T_j=25^{\circ}C)$	80	mΩ
$R_{DS(on), typic}(T_j=25^{\circ}C, I_D=20 A)$	65	mΩ
$I_D(T_j=25^{\circ}C)$	45	A
$Q_g, typic$	62	nC
$Q_{rr}, typic$	1.2	μC
$t_{rr}, typic$	110	ns
$T_{j, max}$	150	°C



Package Feature

Order code	Marking	Package	Packing
LX1S080N065FBW	LX1S080N065FB	TO-247-3PIN	Tube



1. Maximum Ratings ($T_J=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DSS}	650	V
Gate-Source Voltage	V_{GSS}	± 30	V
Continuous Drain Current	I_D	$T_C=25^\circ\text{C}$	45
		$T_C=100^\circ\text{C}$	29
Pulsed Drain Current (Note 2)	I_{DM}	135	A
Avalanche Energy, Single Pulse (Note 3)	E_{AS}	1190	mJ
Avalanche Energy, Repetitive (Note 2)	E_{AR}	1.7	mJ
Avalanche Current, Repetitive (Note 2)	I_{AR}	8.8	A
Continuous Diode Forward Current	I_S	45	A
Diode Pulse Current	$I_{S,pulse}$	135	A
MOSFET dv/dt Ruggedness, $V_{DS}\leq 400\text{V}$	dv/dt	80	V/ns
Reverse diode dv/dt Ruggedness, $V_{DS}\leq 400\text{V}$	dv/dt	50	V/ns
Power Dissipation	P_{tot}	390	W
Operating Temperature/ Storage Temperature	T_J	-55~150	$^\circ\text{C}$

Note:

1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature
3. $I_{AS} = 8.8\text{A}$, $V_{DD} = 50\text{V}$, $R_g = 25\Omega$, Starting $T_J = 25^\circ\text{C}$

2. Thermal characteristics (TO247 Package)

Parameter	Symbol	Max. Value	Unit
Thermal resistance, junction-to-case	R_{thJC}	0.32	$^\circ\text{C/W}$
Thermal resistance, junction-to-ambient	R_{thJA}	62	$^\circ\text{C/W}$

3. Electrical Characteristics ($T_{vj}=25^{\circ}\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Statistic Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	650			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 650\text{ V}, V_{GS} = 0\text{ V}$			10	μA
Gate-Source Leakage Current	I_{GSSF}	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$			100	nA
	I_{GSSR}	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$			-100	nA
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = 1.5\text{ mA}$	3.8	4.3	4.8	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{ V}, I_D = 20\text{ A}$		65	80	m Ω
		$V_{GS} = 10\text{ V}, I_D = 20\text{ A}$ $T_j = 125^{\circ}\text{C}$		140		
Gate Resistance	R_G	$f = 1\text{ MHz}, \text{ open drain}$		3.0		Ω
Dynamic Characteristics						
Input Capacitance	C_{ISS}	$V_{GS} = 0\text{ V}$ $V_{DS} = 100\text{ V}$ $f = 1\text{ MHz}$		4300		pF
Output Capacitance	C_{OSS}			150		
Reverse Transfer Capacitance	C_{RSS}			1		
Gate to Source Charge	Q_{gs}	$V_{DS} = 520\text{ V}$ $V_{GS} = 0\text{ to }10\text{ V}$ $I_D = 20\text{ A}$		25		nC
Gate to Drain Charge	Q_{gd}			13		
Gate Charge Total	Q_g			62		
Switching Characteristics						
Turn-on delay time	$T_{d(on)}$	$V_{DD} = 400\text{ V}, I_D = 20\text{ A},$ $R_G = 10\Omega, V_{GS} = 0/10\text{ V}$		150		ns
Rise time	T_r			20		
Turn-off delay time	$T_{d(off)}$			125		
Fall time	T_f			6		
Turn-on switching energy	E_{on}				1.2	
Turn-off switching energy	E_{off}			0.6		
Reverse Diode Characteristics						
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS} = 0\text{ V}, I_{SD} = 20\text{ A}$		0.9		V
		$V_{GS} = 0\text{ V}, I_{SD} = 20\text{ A}$ $T_j = 125^{\circ}\text{C}$		0.8		
Reverse Recovery Time	t_{rr}	$V_R = 400\text{ V}, I_F = 20\text{ A},$ $di/dt = 150\text{ A}/\mu\text{s}$		110		ns
Reverse Recovery Charge	Q_{rr}			1.2		μC
Peak Reverse Recovery Current	I_{rrm}			15		A



4. Electrical characteristic curves

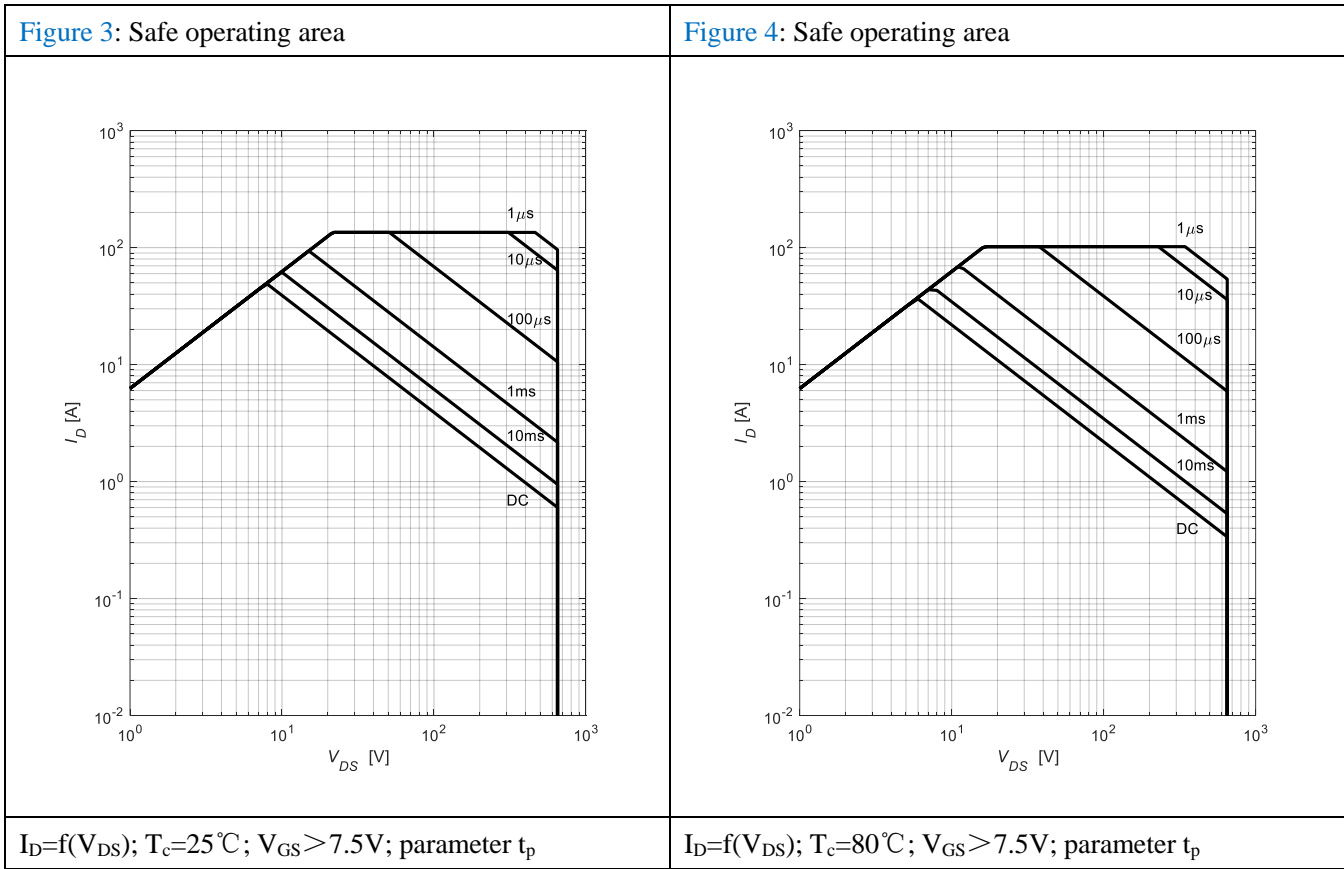
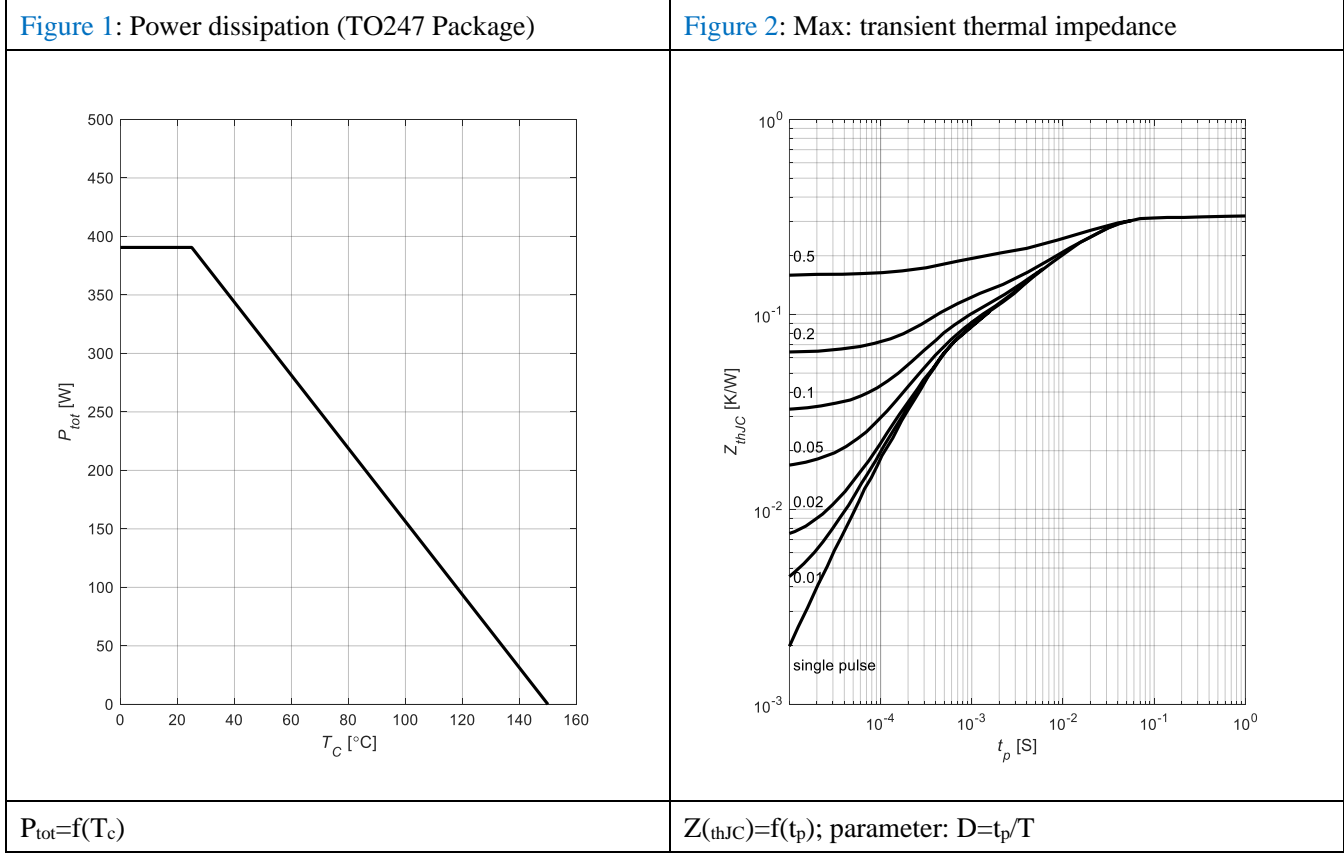
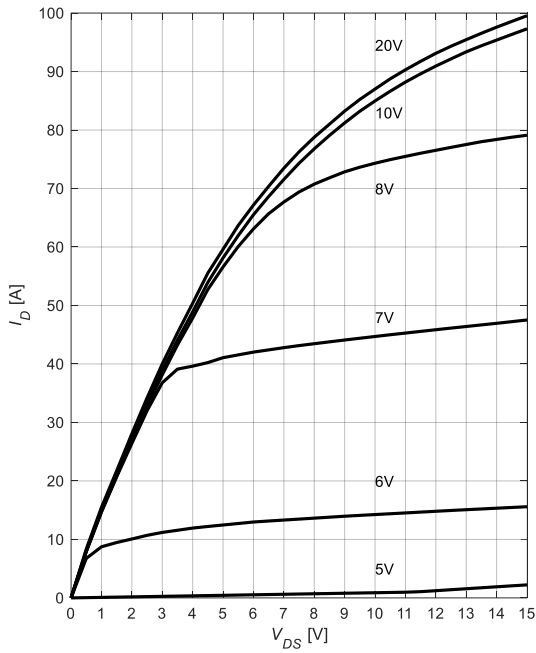
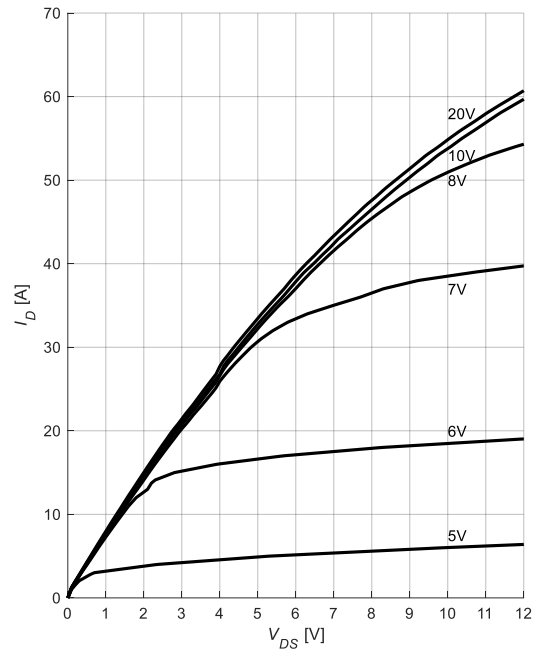


Figure 5: Typ. output characteristics



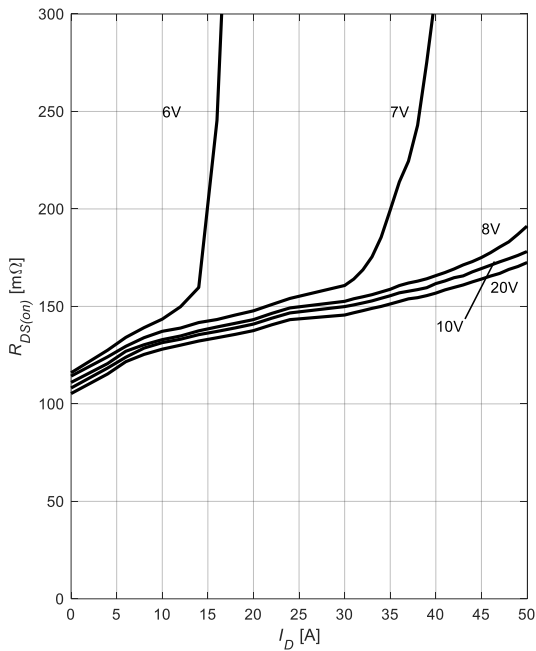
$I_D=f(V_{DS})$; $T_j=25^\circ\text{C}$; parameter: V_{GS}

Figure 6: Typ. output characteristics



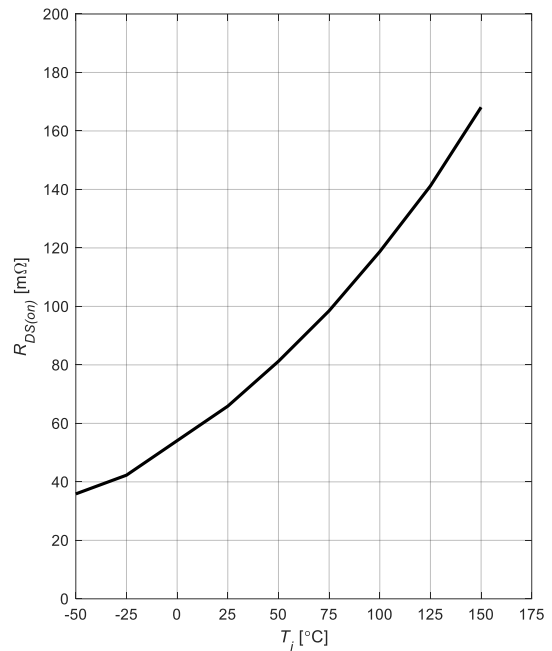
$I_D=f(V_{DS})$; $T_j=125^\circ\text{C}$; parameter: V_{GS}

Figure 7: Typ. Drain-Source On-State Resistance



$R_{DS(on)}=f(I_D)$; $T_j=125^\circ\text{C}$; parameter: V_{GS}

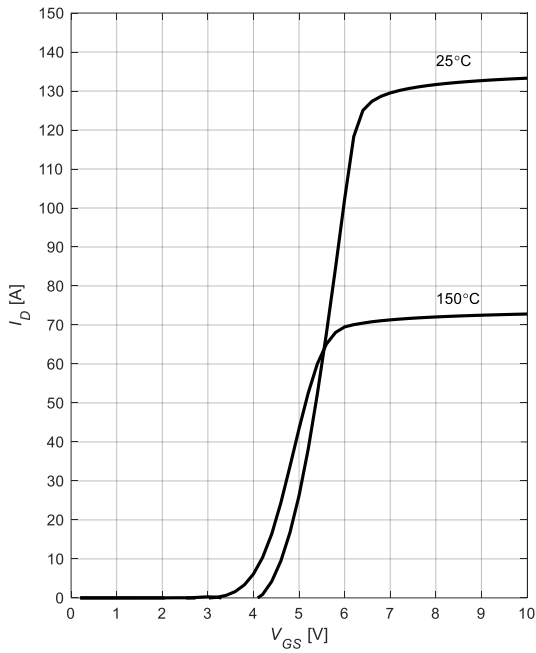
Figure 8: Typ. Drain-Source On-State Resistance



$R_{DS(on)}=f(T_j)$; $I_D=20\text{A}$; $V_{GS}=10\text{V}$

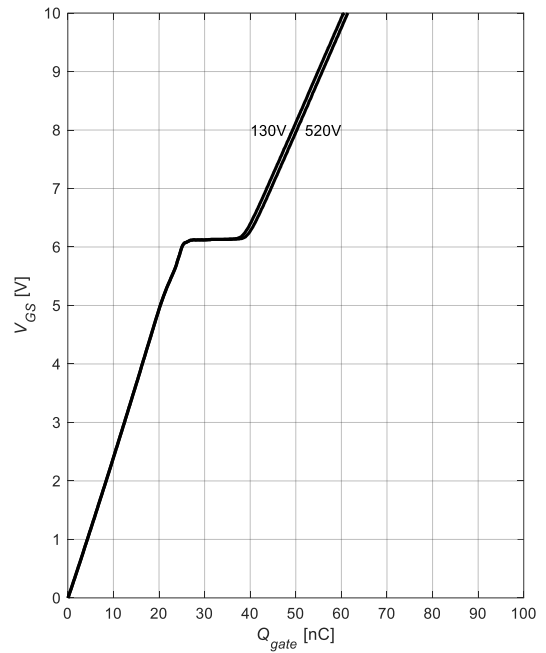


Figure 9: Typ. transfer characteristics



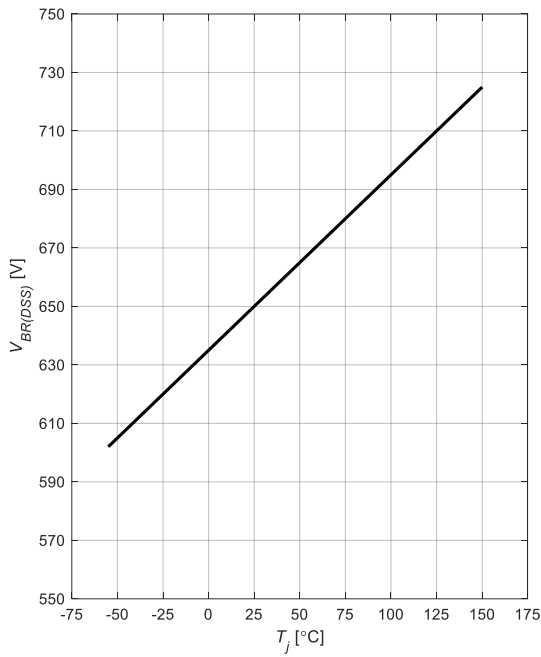
$I_D=f(V_{GS}); V_{DS}=20V$

Figure 10: Typ. gate charge



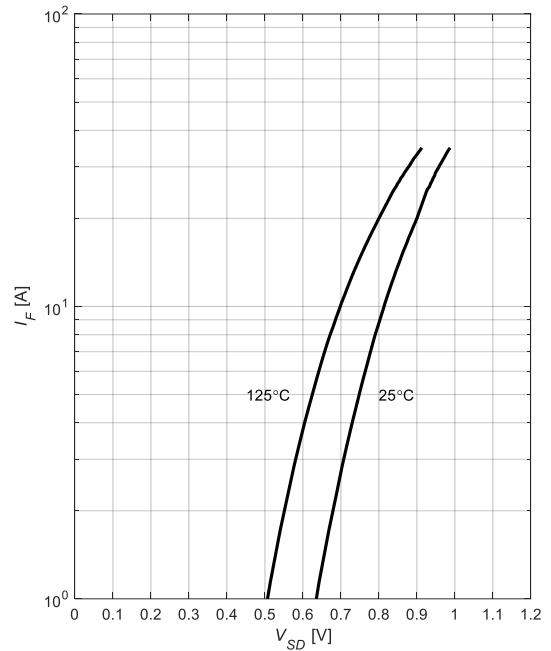
$V_{GS}=f(Q_{gate}), I_D=20A$ pulsed

Figure 11: Drain-source breakdown voltage



$V_{BR(DSS)}=f(T_j); I_D=1mA$

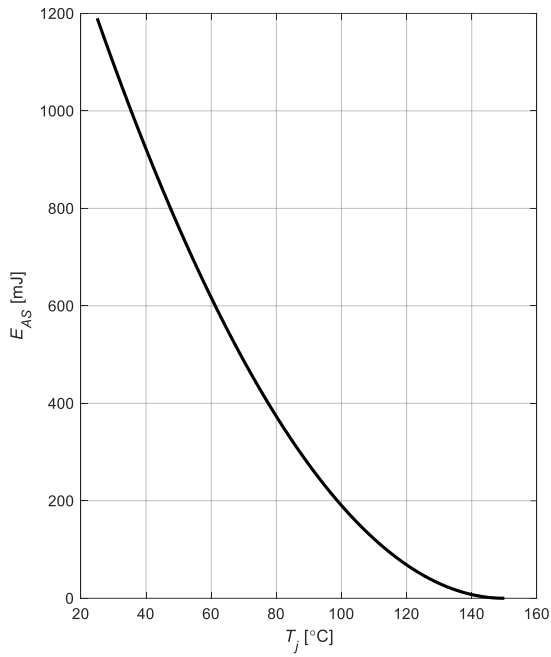
Figure 12: Forward characteristics of reverse diode



$I_F=f(V_{SD});$ parameter: T_j

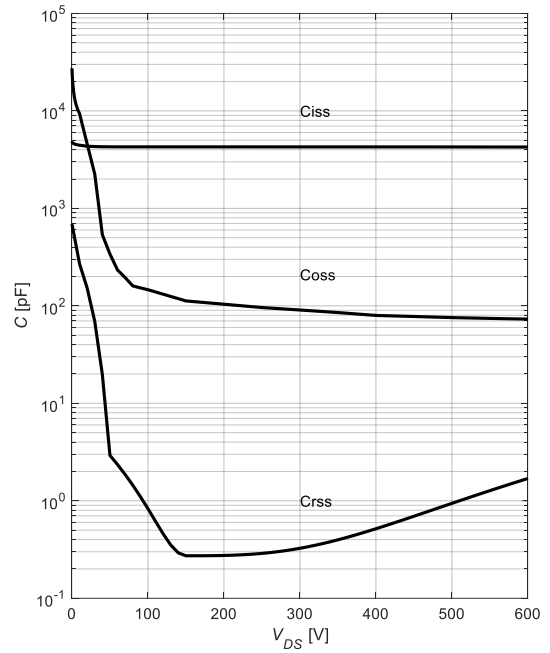


Figure 13: Avalanche energy



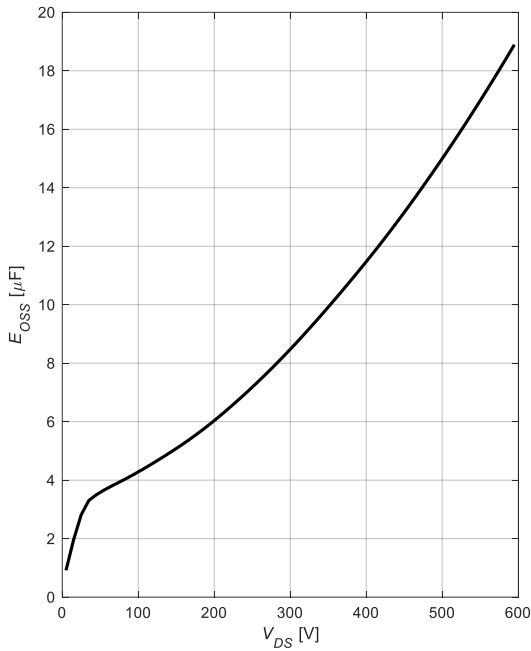
$E_{AS}=f(T_j)$; $I_D=8.8A$; $V_{DD}=50V$

Figure 14: Typ. capacitances



$C=f(V_{DS})$; $V_{GS}=0$; $f=1MHz$

Figure 15: C_{OSS} stored energy

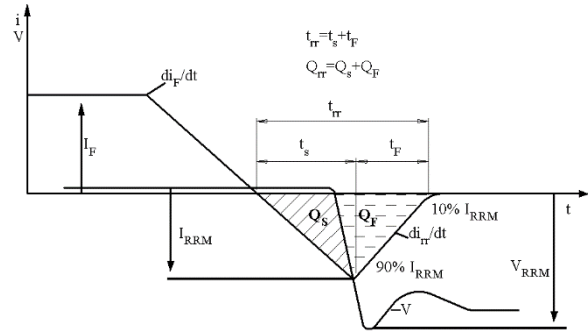
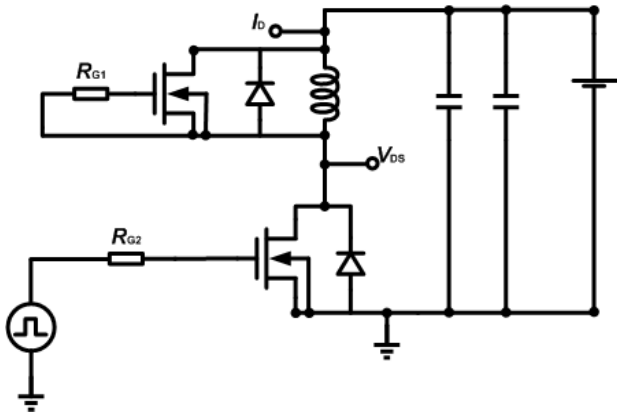


$E_{OSS}=f(V_{DS})$

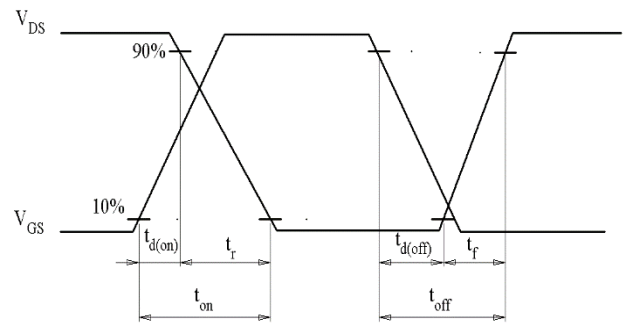
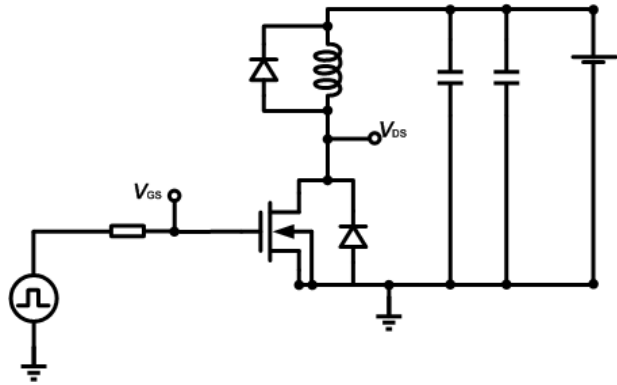


5. Test Circuits

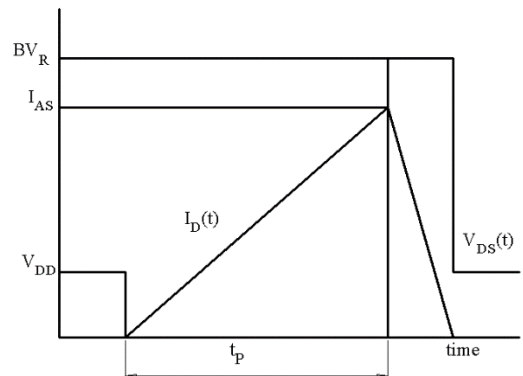
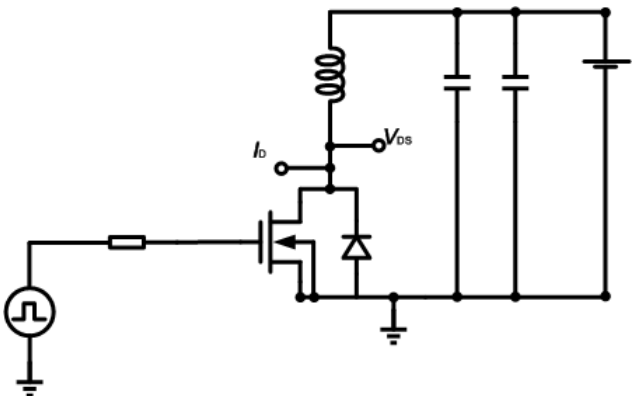
1) Test circuit and waveform for diode characteristics



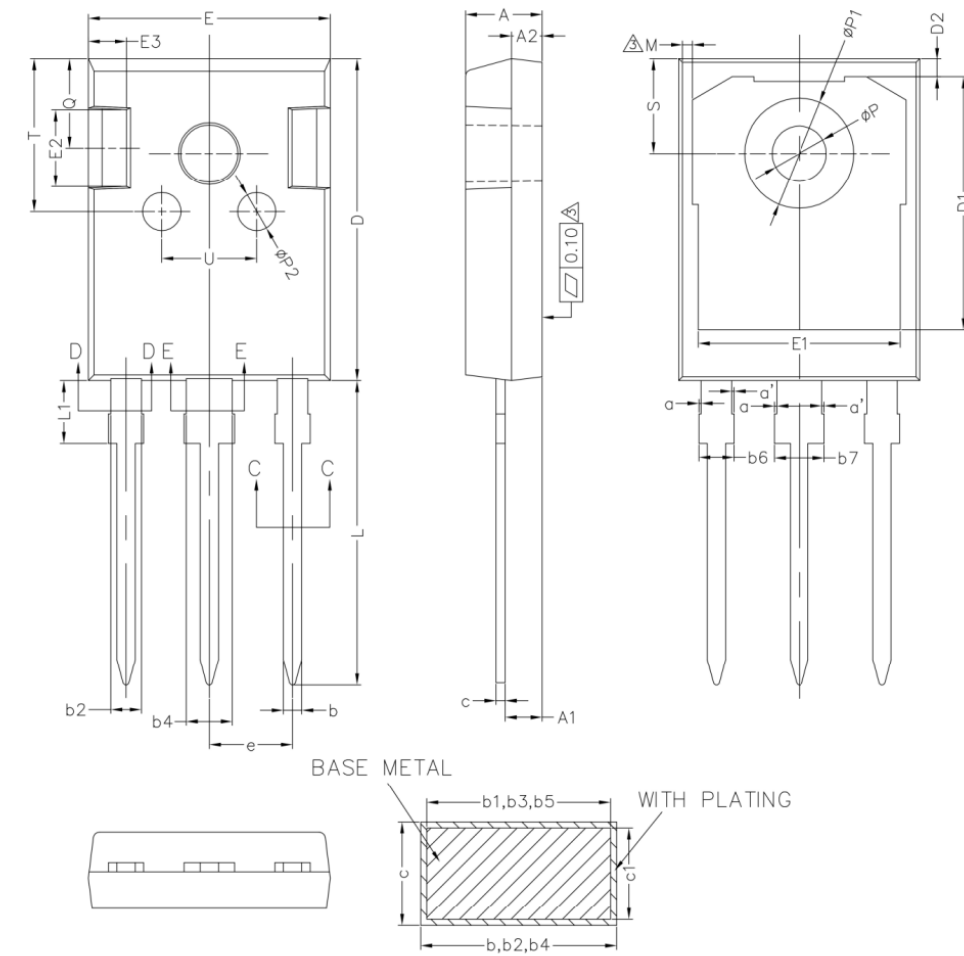
2) Switch time test circuit



3) Unclaimed inductive switching test circuit & waveforms



6.Package outline dimensions



COMMON DIMENSIONS
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
a	0	-	0.15
a'	0	-	0.15
b	1.16	-	1.26
b1	1.15	1.2	1.22
b2	1.96	-	2.06
b3	1.95	2.00	2.02
b4	2.96	-	3.06
b5	2.95	3.00	3.02
b6	-	-	2.25
b7	-	-	3.25
c	0.59	-	0.66
c1	0.58	0.60	0.62
D	20.90	21.00	21.10
D1	16.25	16.55	16.85
D2	1.05	1.20	1.35
E	15.70	15.80	15.90
E1	13.10	13.30	13.50
E2	4.90	5.00	5.10
E3	2.40	2.50	2.60
e	5.34	5.44	5.54
L	19.80	19.92	20.10
L1	3.95	4.13	4.30
M	0.35	-	0.95
P	3.50	3.60	3.70
P1	7.00	-	7.40
P2	2.40	2.50	2.60
Q	5.60	-	6.00
S	6.05	6.15	6.25
T	9.80	-	10.20
U	6.00	-	6.40

NOTES:
 1.ALL DIMENSIONS REFER TO JEDEC STANDARD TO-247 AD DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS.
 2.EJECTION MARK DEPTH 0.10±0.15/0.05.



7.Revision History

Revision	Description	Date
1.0	Initial version	2023/09/06

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